



ACCEDE | ESCCON

2025

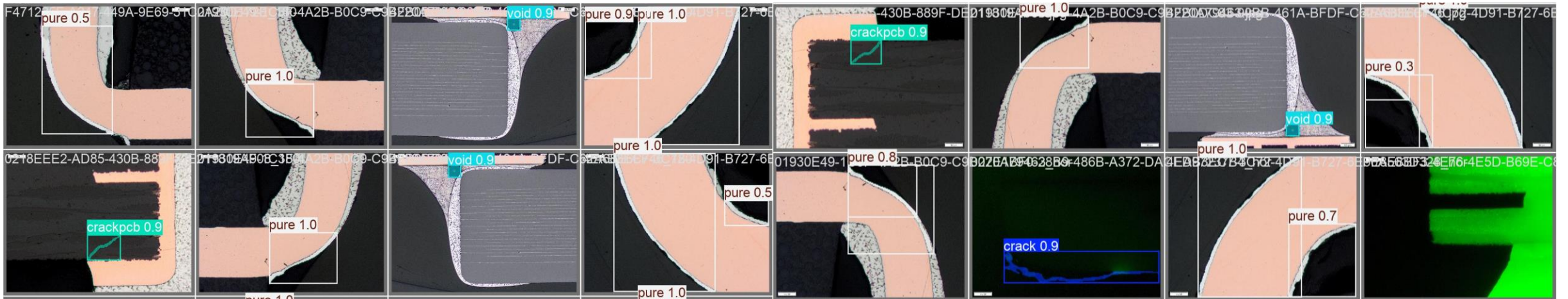
Seville - Spain
25 to 27th March

ALTER | 



Revolutionizing PCB Soldering Verification with Computer Vision

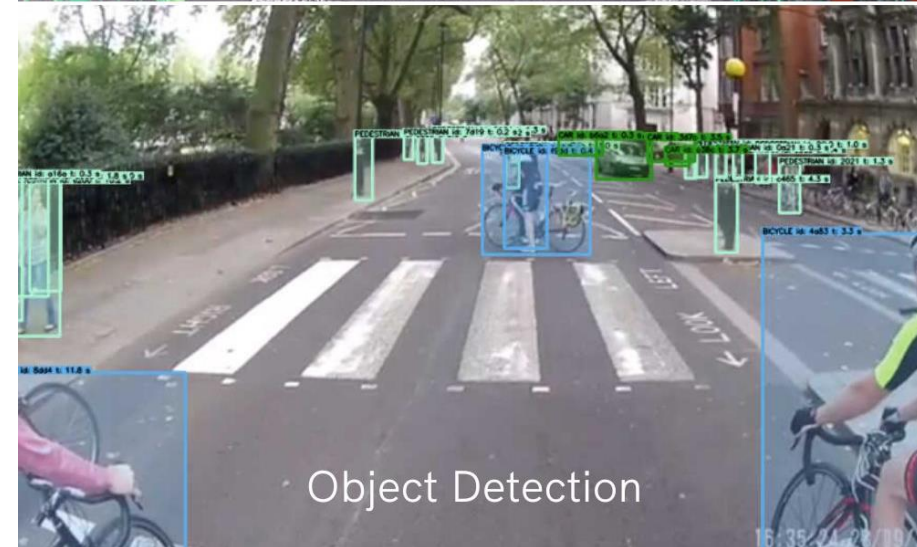
MC. López, M. Dominguez



INTRODUCTION

Computer Vision

- Computer vision is **a field of artificial intelligence** that combines **machine learning** and **neural networks** to teach computers and systems to extract information from digital images, videos and other visual inputs,
- **Machine learning** uses algorithmic models that allow a computer to learn on its own about **the context of visual data.**
- A **convolutional neural networks** helps a machine learning or deep learning model 'look' by decomposing images into pixels that are assigned labels.



INTRODUCTION

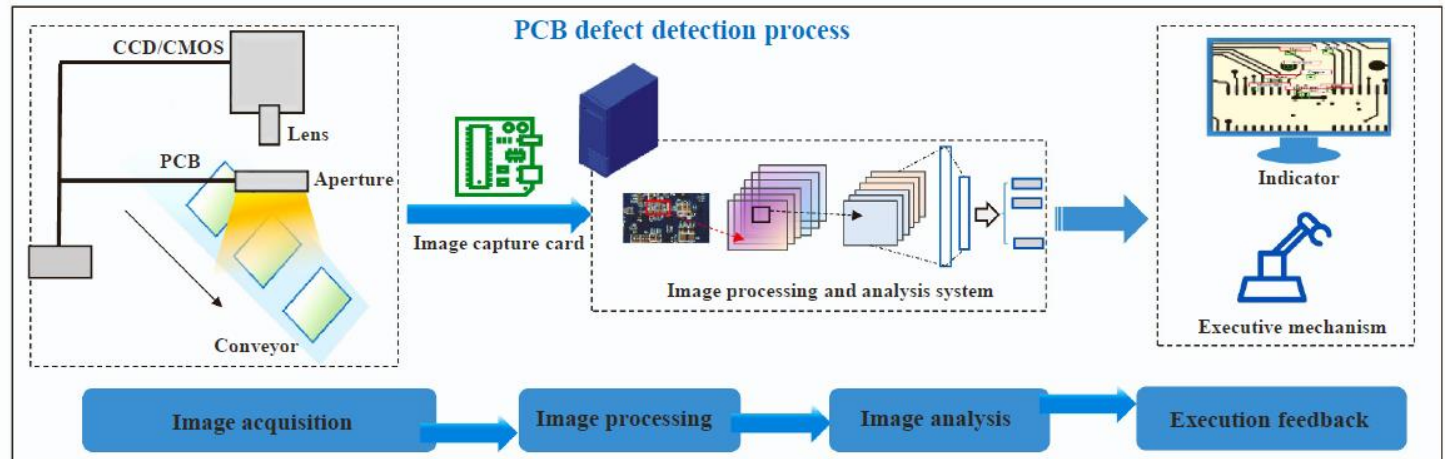
Computer Vision in PCB industry

- Automatic Optical Inspection (AOI) during the PCB design, manufacturing or assembly is widely used by the industry since 1980 s.

- Main process monitoring by computer vision:

- **Circuit printing**
- **Component placement**
- **Component soldering**

- Current automated inspections combine dedicated computer hardware and advanced cameras.



- How this algorithm works?

- **Referential approach:** compare between pixels in the test image and in a template image.
- **Non-referential approach:** work on geometry shapes and verify the design rules.
- **Hibrid approach**

TY. Zhou, M. Yuan, J.Zhang, G.Ding, S.Qin. Journal of Manufacturing Systems 70 (2023) 557-578.

N.Petkov, M.Ivanova. Printed circuit board and printed circuit board assembly methods for testing and visual inspection: a review. Bulletin of electrical Engineering and Informatics, Vol 13, N4 (2024) 2566-2585

INTRODUCTION



Materials & Processes Laboratory



Accreditations

- **ESA recommended Microsectioning Laboratory** in accordance with ESA-TECMSP-MO-013165 memo.
- **ISO/IEC 17025:2017** accredited for PCB Testing in accordance with 345/LE2116 certificate.



Capabilities

- Qualification PCB
- Qualification assembled PCB
- Press-fit connector Qualification
- Wire crimping Evaluation
- Component microsectioning analysis



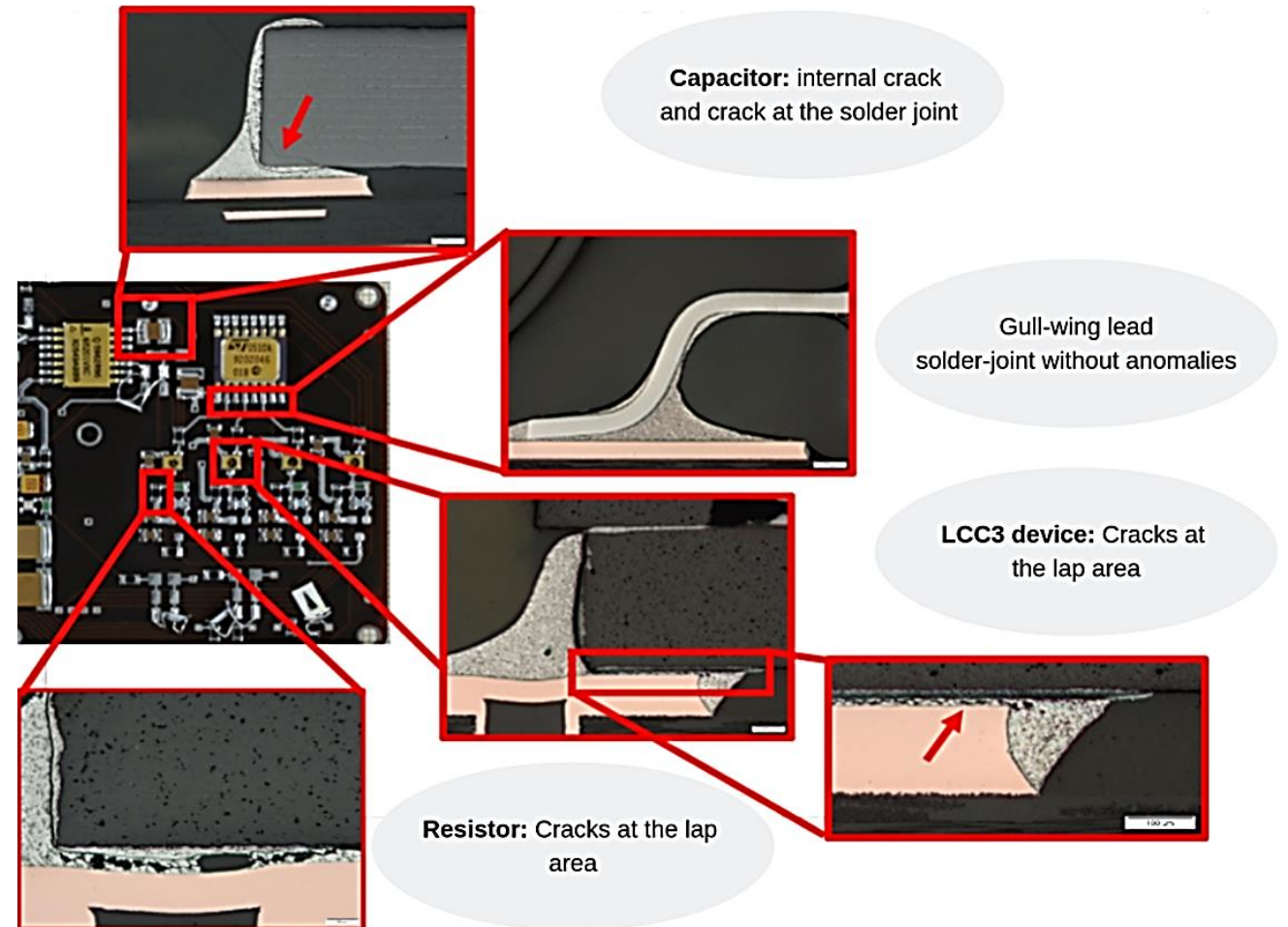
Technician expertise

- **ESA certified inspectors** for ECSS-Q-ST-70-08C, ECSS-Q-ST-70-38C & ECSS-Q-ST-70-26C
- **IPC certified inspector** IPC-600 & IPC-610



Solder Microsection Anomalies

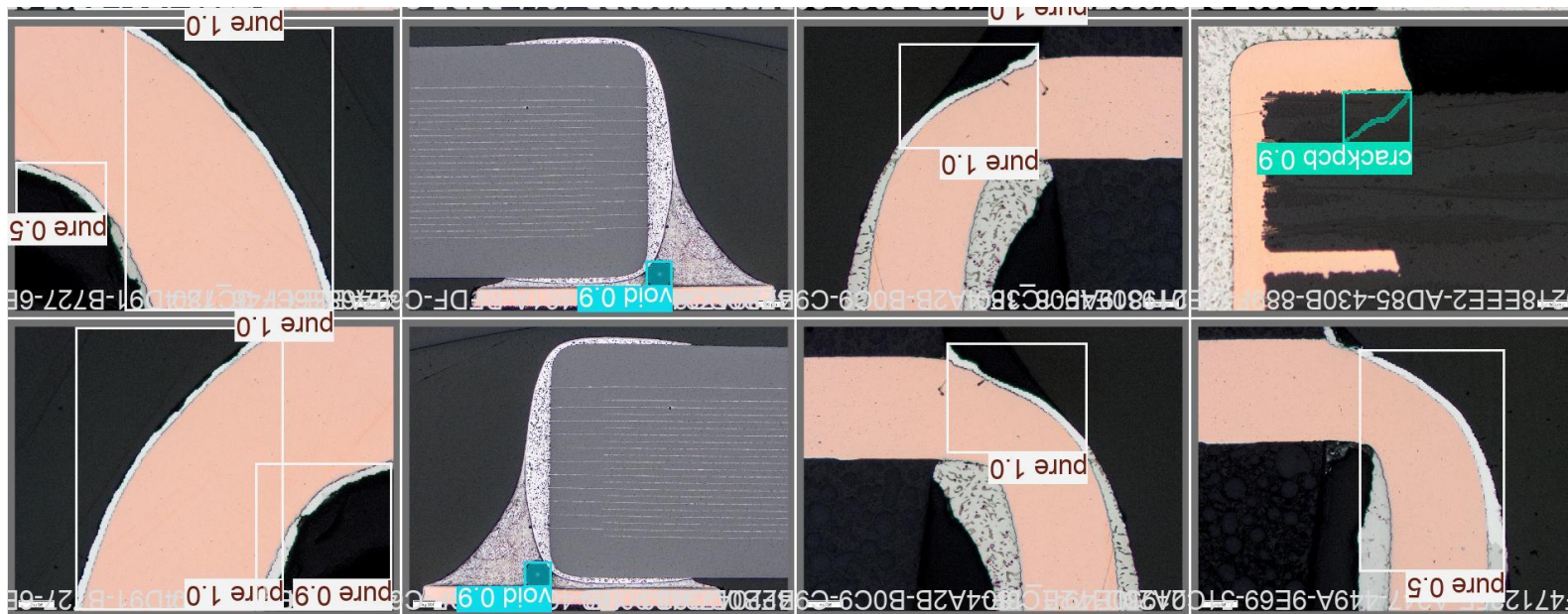
- **Microsection** evaluation of solder joint has become an essential practice for guaranteeing the durability and reliability of the final product.
- **Microsection** test is performed after thermal and mechanical stress helps to detect potential defects before they become critical issues in the field.



GOALS

The aim of this study is:

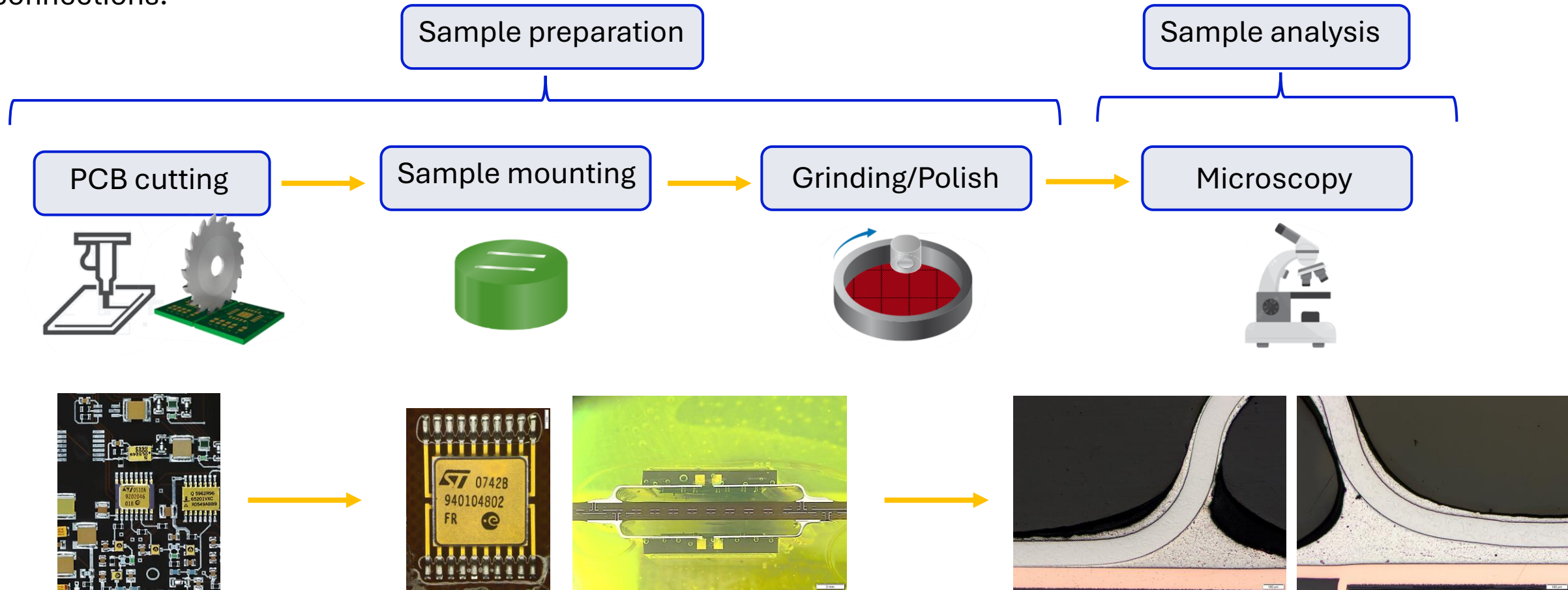
- To **develop a tool** that will assist the inspector in analysing defects in the solder connection of PCB.
- **Design a training/test dataset** to give to the tool the enough experience to be able to work with different scenarios.
- **Harmonisation** of the criteria to evaluate anomalies in solder connections.
- To **optimize** the time dedicated to evaluating images of solder connections.



EXPERIMENTAL PROCEDURE



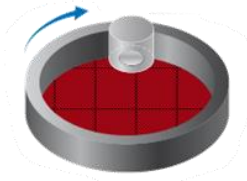
As **ESA recommended facilities** to perform microsection analysis as part of the qualification programme for assembled PCB, the laboratory of Materials and Processes has been analyzed more than **30.000** solder connections.



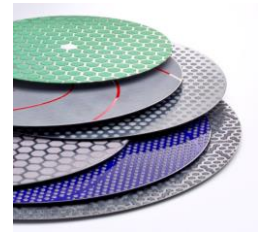
EXPERIMENTAL PROCEDURE

ALTER

Grinding/Polish

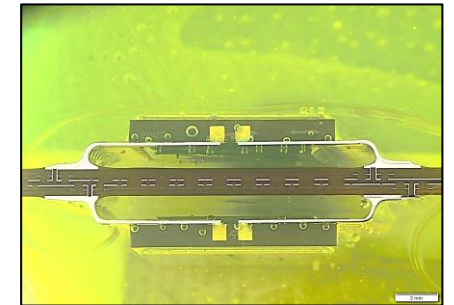
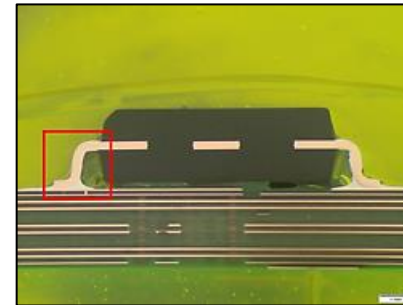
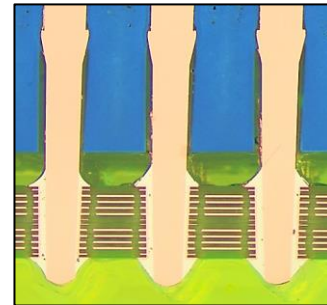
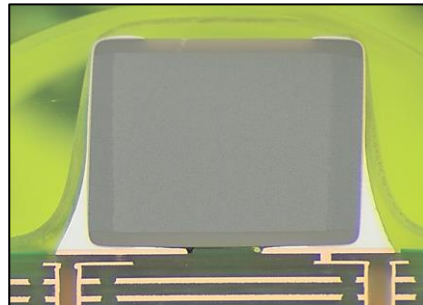
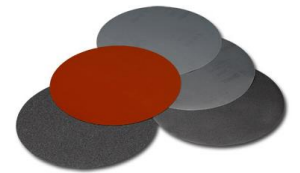


ALTER Technology has developed different **grinding protocols depending on the device** and based on the component materials of the device.



These methods define each **parameter** during the process, like:

- Abrasive Surface
 - Diamond coated bases
 - SiC sandpapers
 - Polishing clothes
- Lubricant
- Rotation Speed
- Pressure
- Time
- Grit size



EXPERIMENTAL PROCEDURE



Sample analysis



- During the last 8 years, we have recorded more than 200,000 images.
- Our digitalization team developed a system to collect all the images and label them according to the anomaly that we detected on the solder connection.

- Although our technicians are experts, reviewing and classifying images one by one is a time-consuming process and subject to human fatigue and error.

- The problem is not only the quantity of images, but also the complexity of the defects: cracks, gaps, contaminants... all different and often subtle.

- **May Computer Vision help us to be more productive?**

The screenshot displays the ALTER Virtual Lab software interface. It features a document navigation tree on the left, a central report area with a table of defects, and a detailed view of a defect on the right. The table includes columns for Standard, Label, Code, Photo Remarks, Result, Part Remarks, and Group of Components Remarks. The detailed view shows a photograph of a PCB with a defect and associated data.

| Standard | Label | Code | Photo Remarks | Result | Part Remarks | Group of Components Remarks |
|------------------------------------------------|--------------------------|------|--------------------------------------------|--------|-------------------------------------------|-------------------------------------------|
| <input type="checkbox"/> ECSS-Q-ST-70-60C Di1 | Crack PCB | CP01 | Acceptable crack in the board. Reje | C | Acceptable crack in the board. Reje | Acceptable crack in the board |
| <input type="checkbox"/> ECSS-Q-ST-70-60C Di1 | Crack PCB | CP02 | Non acceptable crack in the board. Rej | NC | Non acceptable crack in the board. Rej | Non acceptable crack in the board |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Cracks | CF01 | Acceptable crack d < 70% (d=X%), I | NC | Acceptable crack d < 70%. Reje | Acceptable crack d < 70%. Re |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Cracks | CF02 | Non acceptable crack in the fillet area I | NC | Non acceptable crack in the fillet area I | Non acceptable crack in the fillet area I |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Cracks | CF04 | Non acceptable crack d > 70% (d=X%), I | NC | Non acceptable crack d > 70%. Reje | Non acceptable crack d > 70%. Re |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Damaged | DO1 | Damaged device. Rejection cause acco | NC | Damaged device. Rejection cause acco | Damaged device. Rejection c |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Damaged | DO2 | Crack in ceramic at the bottom edge o | NC | Crack in ceramic at the bottom edge o | Crack in ceramic at the bottom |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Detachment | DA01 | Detachment of the termination. Reje | NC | Detachment of the termination. Reje | Detachment of the terminati |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Foatprint | FO01 | The terminal of the device does not lie | NC | The terminal of the device does not lie | The terminal of the device d |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Incomplete degolding | ID01 | SnAu intermetallics in solder joint. Ino | NC | SnAu intermetallics in solder joint. Ino | SnAu intermetallics in solder |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Incomplete wetting | IW01 | Incomplete wetting. | TBD | Incomplete wetting. | Incomplete wetting. |
| <input type="checkbox"/> ECSS-Q-ST-70-38C Rev1 | Insufficient solder | IS01 | Insufficient solder. Rejection criteri | NC | Insufficient solder. Rejection criteri | Insufficient solder. Rejection |
| <input type="checkbox"/> | Microsectioning artefact | MI01 | Damages in the glass body produced c | C | | |
| <input type="checkbox"/> | Microsectioning artefact | MI02 | Regular voids (artifacts) are the result c | C | | |
| <input type="checkbox"/> | Microsectioning artefact | MI03 | Scratches caused during the grinding p | C | | |
| <input type="checkbox"/> | Others | OO1 | Acceptable anomaly. | C | | |
| <input type="checkbox"/> | Others | OO2 | Non acceptable anomaly. | NC | | |
| <input type="checkbox"/> ECSS-Q-ST-70-60C Di1 | Overhang | OO1 | Acceptable metal overhang, D ≤ 2x tot. | C | Acceptable metal overhang, D ≤ 2x tot. | Acceptable metal overhang, |
| <input type="checkbox"/> ECSS-Q-ST-70-60C Di1 | Overhang | OO2 | Non acceptable metal overhang, D > 2x | NC | Non acceptable metal overhang, D > 2x | Non acceptable metal overh |
| <input type="checkbox"/> | Voids | VO1 | Voids in the solder area. | C | Voids in the solder area. | Voids in the solder area. |



Certified IPC-A-600
Application Specialist



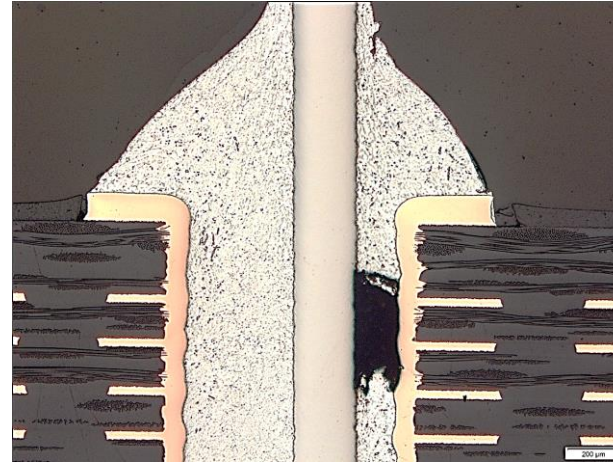
Certified IPC-A-610
Application Specialist

RESULTS

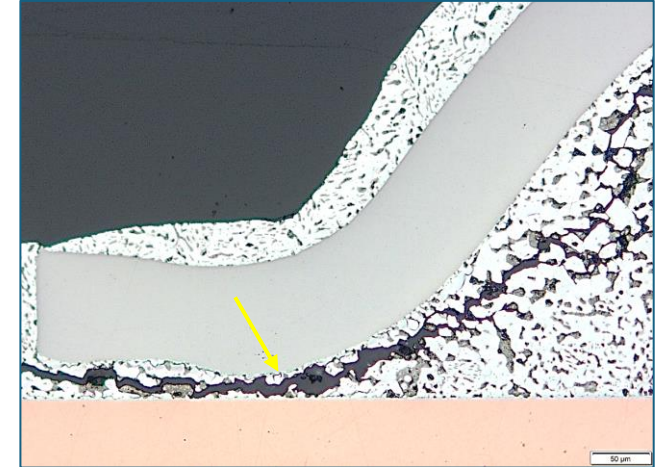
Anomalies under study

- Voids
- Crack in solder joint
- Cracks in PCB
- Poor degolding process
- Pure Tin

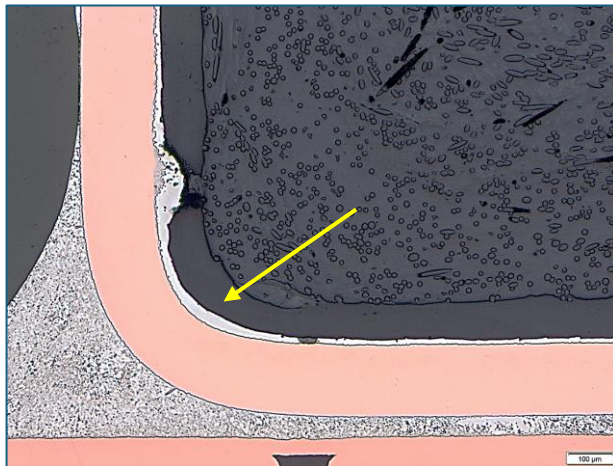
Voids



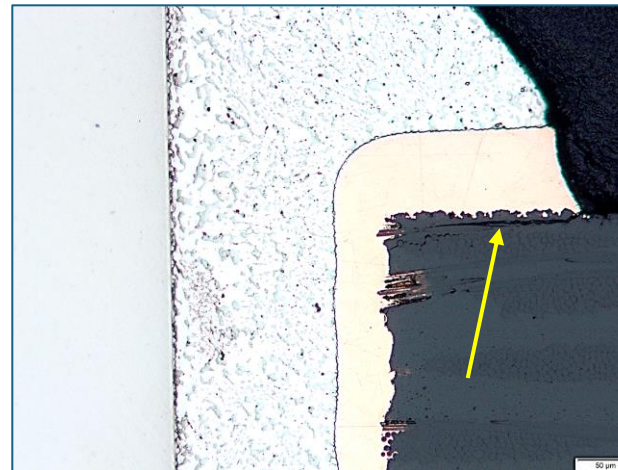
Crack in Solder joint



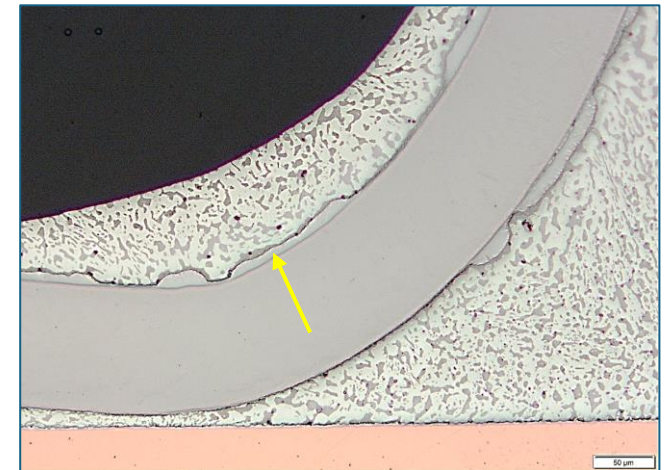
Pure tin



Crack in PCB



Poor degolding process



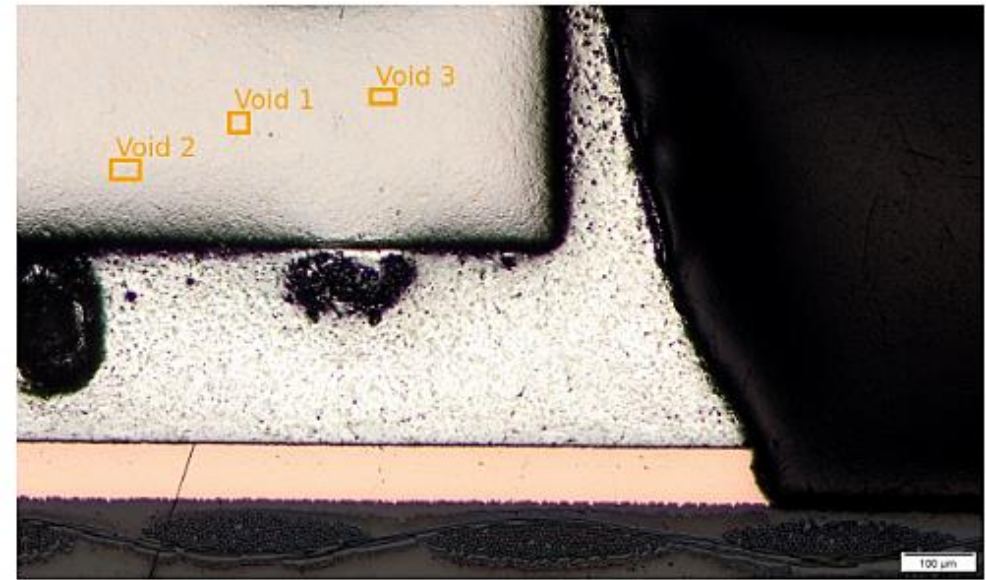
First round: Chat GPT

- Due to the complexity of the anomalies we can find in a solder joint, a simple defect was chosen to begin with: **Voids in solder joint.**



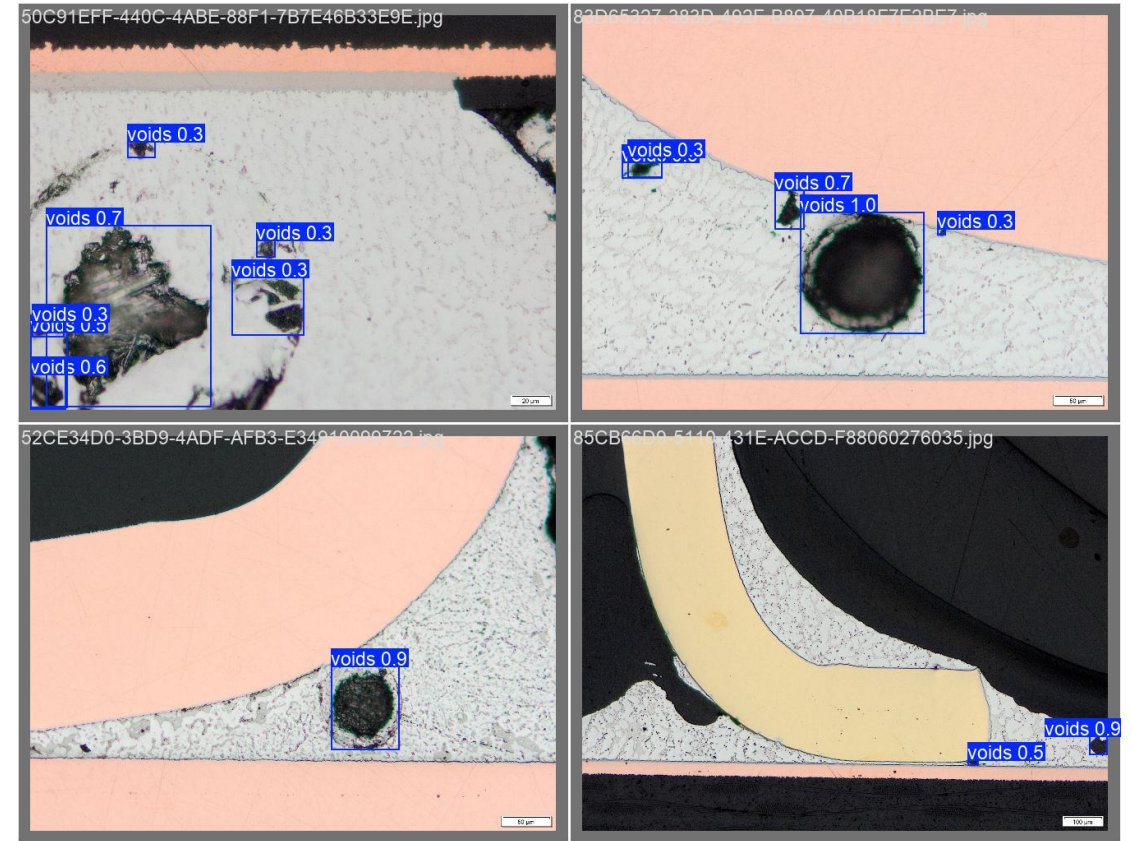
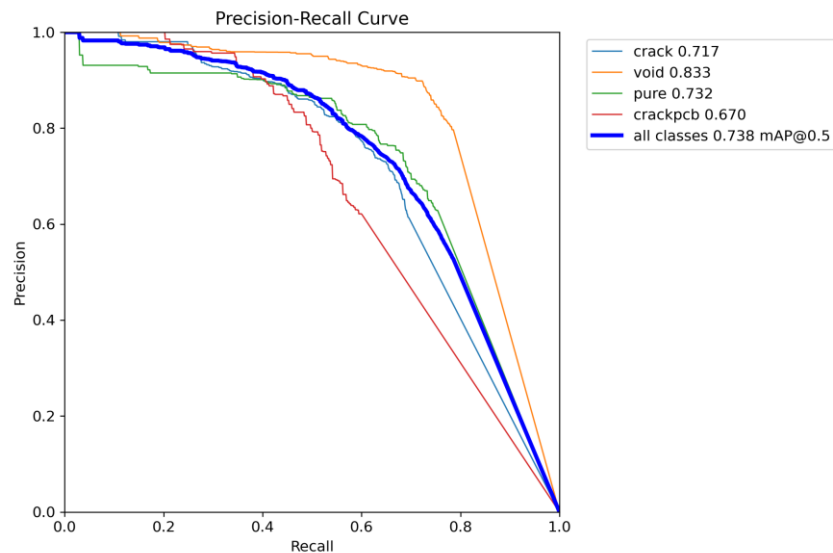
- The standard ChatGPT fails to identify the most evident anomalies in the picture.

- Although ChatGPT understands the acceptance criteria and the quality of the picture seems good enough, the results are totally unacceptable.



Second Round: Single anomaly detection

- We have hundreds of images classified with the label **VOID**. These images are used to train the system to recognize a black hole in the SnPb solder like a void.
- Once we have classified hundred of pictures with one single anomaly, voids, it seems that **the model is able to identify** most of them and evaluate the degree of confidence that could be provided.



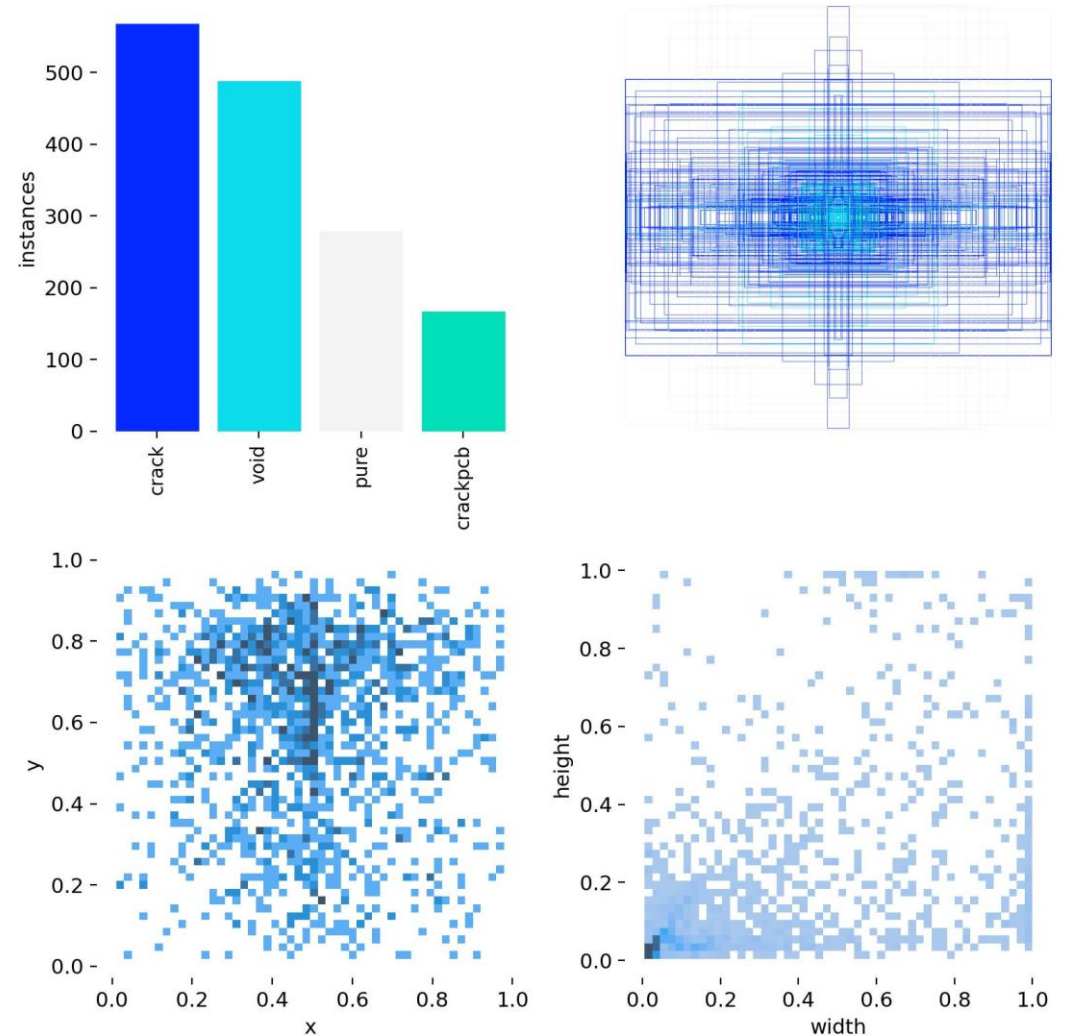
RESULTS

Data Quality

The **conclusions** after analyzing the images obtained by the Materials and Processes Laboratory are the following:

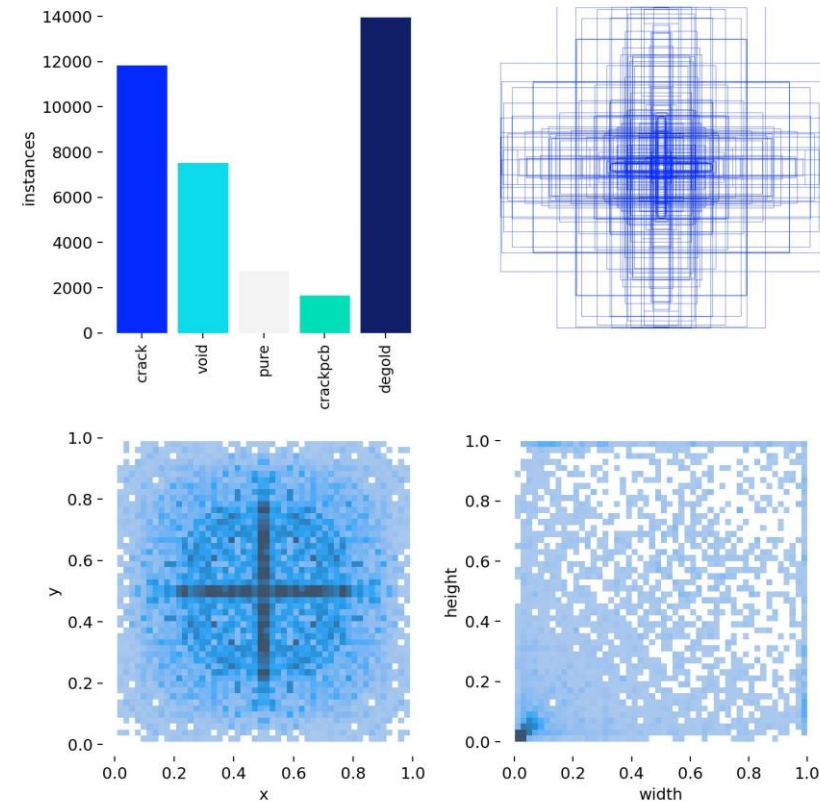
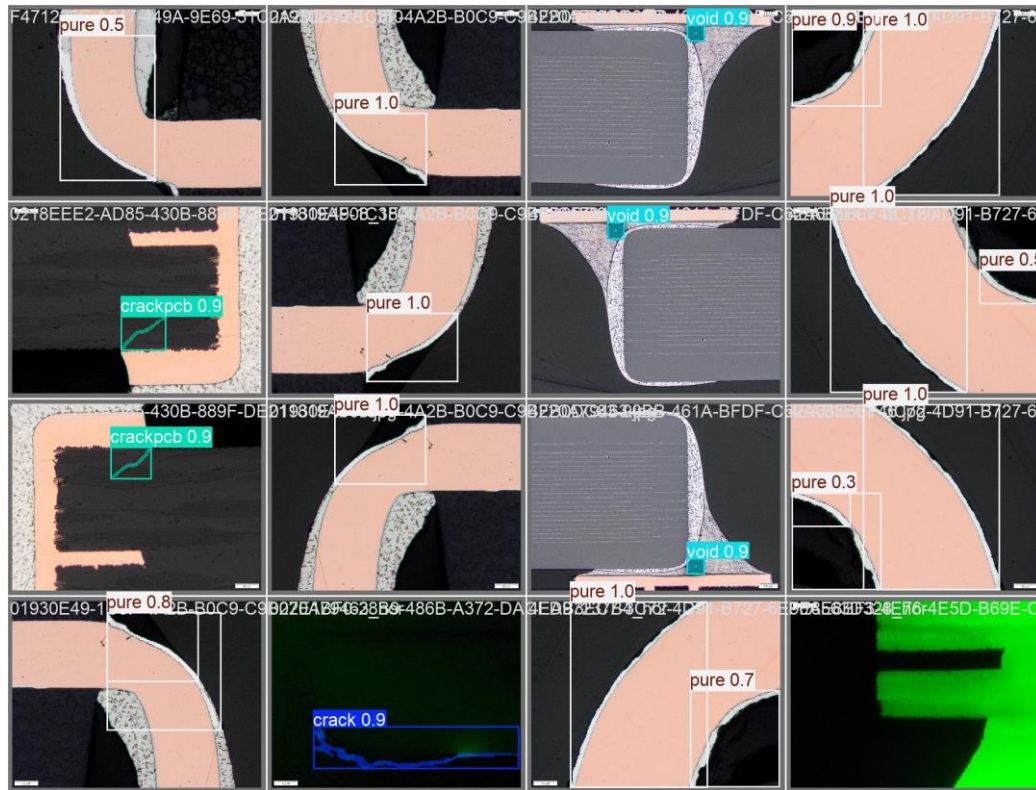
- The **most** provable **anomaly** is the presence of **crack** in the solder connections.
- The extent of the **anomaly** is **small** compared to the size of the image.
- The **location** of the anomaly is typically **centered** in the image.

These data have to be read as the bias of our system.



Third Round: Everything at once

- For the **training stage**, synthetic data were generated. This type of data allow us to generate datasets based on **real-world events** that are more accurate representations of these events.
- Synthetic data allow to learn with greater accuracy and diversity.



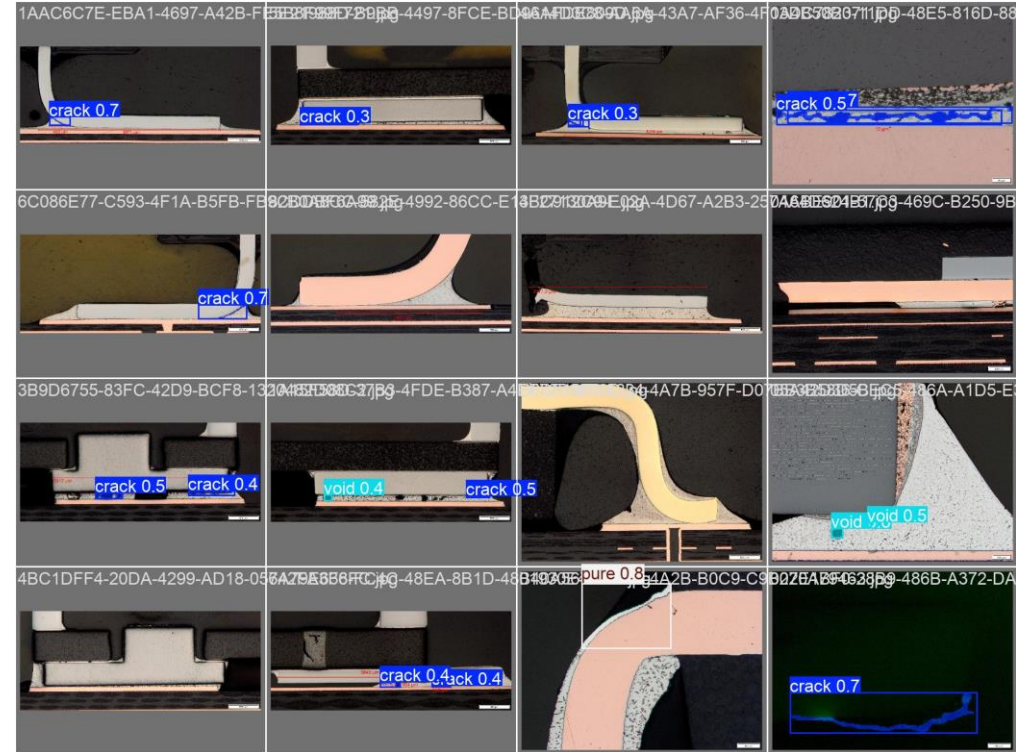
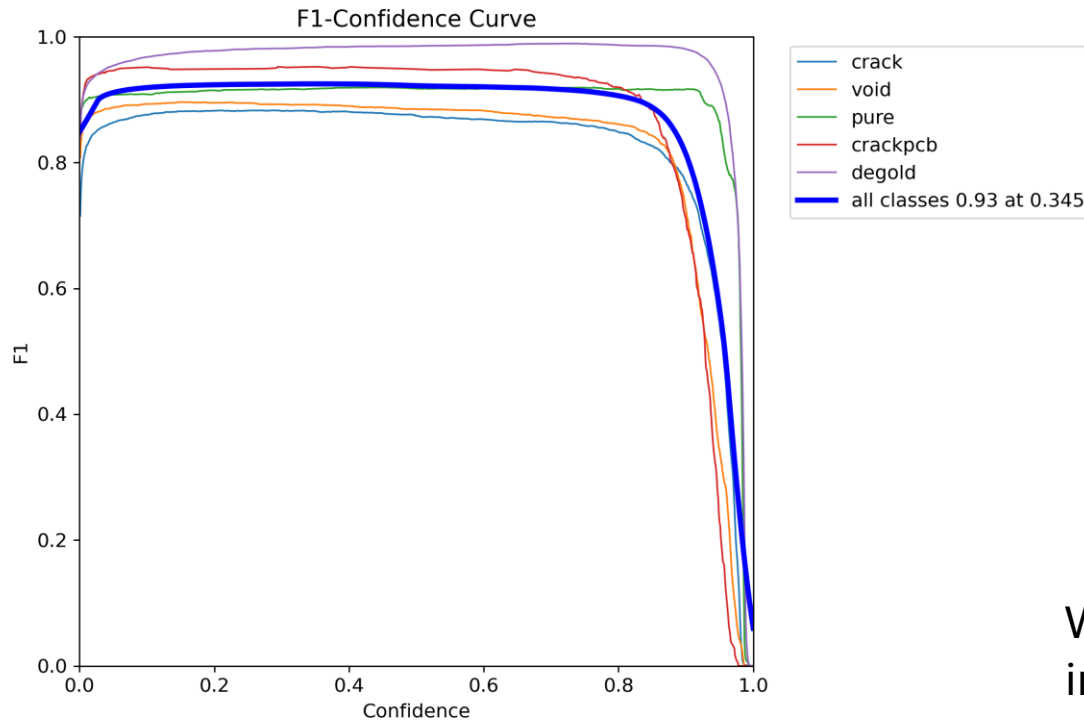
RESULTS

Third Round



Third Round: Everything at once

- This new training allows:
 - Improve the degree of **fulfillment** of the system.
 - Provide the **ability to predict** rare events.



With the **current results**, the **model** has not only met the initially defined standards but has **exceeded them!!**

- A tool base on **Computer Vision** models has been developed to analyse the potential anomalies of solder connections as a part of the daily work of the Laboratory of Materials and Processes.
- From a technical point of view, optimal preparation of the sample to be analysed is key to obtaining high quality images to be analysed with this new method.
- We have creating **training/testing sets** to lay the foundation of our Computer Vision tool .
- With the current results, the model has not only met the initially defined standards but has exceeded them in several key metrics. This indicates that **the model could be commercially viable** and capable of meeting expectations in real-world applications



Thank you for your attention.



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